Sheet 1 of 1

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IΔN 1 7 2004	2)						APPLICANT Walton et al							
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i.	*EXAMINER INITIAL /C.A./ B1		PUBLICATION NUMBER		PUB. DATE		NAME		CLASS	SUB CLAS		FILING DATE IF APPROPRIATE		
			2004/0002364 A1		1/1/04	Trikkonen et al			455	562.1				
	/C.A./	B2	2003/0128658 A1	03/0128658 A1		Walt	Valton et al		370	208				
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OTHER PRIOR ART (Including Author, Title, Date, Pertinent Page, Etc.)														
	/C.A./ D1 Laroia et al, "ENHANCED OPPORTUNISTIC BEAMFORMING", 2003, PGS 1762-1766									5				
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	*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.													